Sheet 1 of 1 APPLICATION NUMBER JAN 1 6 2001 GROUP ART UNIT Q4DEMP Filing Date

FORM PT9-1449 (Modified)

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ATTY, DOCKET NO. TS0926 (US)

APPLICANT

M. B. H. Van Criinen-Beers

09/664,293

FILING DATE September 18, 2000

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS Examiner Document No. Date **Patentee** Class **Subclass** if Appropriate Initial 10/1/91 502 AA Absil et al. 64 5,053,374 WB 533 AB 5,157,191 10/20/92 Bowes et al. 585 wG 7/7/64 208 120 AC 3,140,249 Plank et al. W6 7/7/64 208 120 Plank et al. AD 3,140,251 WG ΑE 3,140,253 7/7/64 Plank et al. 208 120 WG 9/8/98 Grandvallet et al. 208 171 AF 5,804,058 WG 9/10/96 208 AG 5,554,274 Degnan et al. 111 WG 585 AH 4,899,011 2/6/90 Chu et al. 48∄ Wb ΑI 5.689.027 11/18/97 Abichandani et al. 585 481 W6 AJ 5,551,956 9/3/96 Moriyama et al. 44 301 W6 FOREIGN PATENT DOCUMENTS **Translation** Document No. Date Country Class **Subclass** WO 96/16005 5/30/96 World 607C 5/22 AL W6 45/64 AM WO 00/29511 5/25/00 World C10G-W6 AN WO 00/29512 5/25/00 **World** C10G 45/64 W6 OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.) AR AS

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The attached cited information should not be construed as an admission that any of the above items are prior art to the subject invention.

This is not a representation that a search has been made. 2.

Cited References) LIST OF INFORMATION PROVIDED BY APPLICANT (Use several sheets if necessary)				TS0926 (US)		SERIAL NO. 09/664,293	
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